



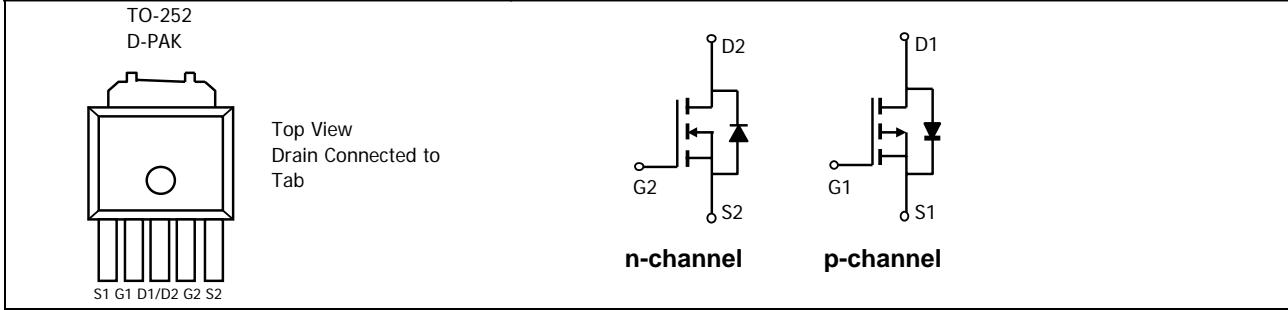
ALPHA & OMEGA
SEMICONDUCTOR



AOD604

Complementary Enhancement Mode Field Effect Transistor

General Description	Features												
<p>The AOD604 uses advanced trench technology MOSFETs to provide excellent $R_{DS(ON)}$ and low gate charge. The complementary MOSFETs may be used in H-bridge, Inverters and other applications. Standard product AOD604 is Pb free (meets ROHS & Sony 259 specifications). AOD604L is a Green Product ordering option. AOD604 and AOD604L are electrically identical.</p>	<table> <tbody> <tr> <td>n-channel</td> <td>p-channel</td> </tr> <tr> <td>V_{DS} (V) = 40V</td> <td>-40V</td> </tr> <tr> <td>$I_D = 8A$ ($V_{GS} = 10V$)</td> <td>-8A ($V_{GS} = -10V$)</td> </tr> <tr> <td>$R_{DS(ON)}$</td> <td>$R_{DS(ON)}$</td> </tr> <tr> <td>< 33 mΩ ($V_{GS} = 10V$)</td> <td>< 50 mΩ ($V_{GS} = -10V$)</td> </tr> <tr> <td>< 47 mΩ ($V_{GS} = 4.5V$)</td> <td>< 70 mΩ ($V_{GS} = -4.5V$)</td> </tr> </tbody> </table>	n-channel	p-channel	V_{DS} (V) = 40V	-40V	$I_D = 8A$ ($V_{GS} = 10V$)	-8A ($V_{GS} = -10V$)	$R_{DS(ON)}$	$R_{DS(ON)}$	< 33 mΩ ($V_{GS} = 10V$)	< 50 mΩ ($V_{GS} = -10V$)	< 47 mΩ ($V_{GS} = 4.5V$)	< 70 mΩ ($V_{GS} = -4.5V$)
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Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted				
Parameter	Symbol	Max n-channel	Max p-channel	Units
Drain-Source Voltage	V_{DS}	40	-40	V
Gate-Source Voltage	V_{GS}	± 20	± 20	V
Continuous Drain Current ^G	$T_C=25^\circ C$	8	8	A
$T_C=100^\circ C$		8	8	
Pulsed Drain Current ^C	I_{DM}	30	-30	
Avalanche Current ^C	I_{AR}	8	-8	A
Repetitive avalanche energy $L=0.1mH$ ^C	E_{AR}	20	30	mJ
Power Dissipation ^B	$T_C=25^\circ C$	20	50	W
$T_C=100^\circ C$		10	25	
Power Dissipation ^A	$T_A=25^\circ C$	2	2.5	W
$T_A=70^\circ C$		1.3	1.6	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 175	-55 to 175	°C

Thermal Characteristics: n-channel and p-channel					
Parameter	Symbol	Device	Typ	Max	
Maximum Junction-to-Ambient ^A	$t \leq 10s$	$R_{\theta JA}$	n-ch	17.4	30 °C/W
Maximum Junction-to-Ambient ^A	Steady-State		n-ch	50	60 °C/W
Maximum Junction-to-Case ^B	Steady-State	$R_{\theta JC}$	n-ch	4	7.5 °C/W
Maximum Junction-to-Ambient ^A	$t \leq 10s$		p-ch	16.7	25 °C/W
Maximum Junction-to-Ambient ^A	Steady-State	$R_{\theta JA}$	p-ch	40	50 °C/W
Maximum Junction-to-Case ^B	Steady-State		p-ch	2.5	3 °C/W

N-Channel MOSFET Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=10\text{mA}, V_{GS}=0\text{V}$	40			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=32\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1	2.3	3	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	30			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=8\text{A}$		25	33	$\text{m}\Omega$
				39	52	
		$V_{GS}=4.5\text{V}, I_D=6\text{A}$		34	47	
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=8\text{A}$		25		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.76	1	V
I_S	Maximum Body-Diode Continuous Current				8	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=20\text{V}, f=1\text{MHz}$		404		pF
C_{oss}	Output Capacitance			95		pF
C_{rss}	Reverse Transfer Capacitance			37		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		2.7		Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=20\text{V}, I_D=8\text{A}$		9.2		nC
$Q_g(4.5\text{V})$	Total Gate Charge			4.5		nC
Q_{gs}	Gate Source Charge			1.6		nC
Q_{gd}	Gate Drain Charge			2.6		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=20\text{V}, R_L=2.5\Omega, R_{\text{GEN}}=3\Omega$		3.5		ns
t_r	Turn-On Rise Time			6		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			13.2		ns
t_f	Turn-Off Fall Time			3.5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=8\text{A}, dI/dt=100\text{A}/\mu\text{s}$		22.9		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=8\text{A}, dI/dt=100\text{A}/\mu\text{s}$		18.3		nC

A: The value of R_{JJA} is measured with the device mounted on 1 in ² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on R_{JJA} and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design, and the maximum temperature of 175°C may be used if the PCB allows it.

B. The power dissipation P_D is based on $T_{\text{J(MAX)}}=175^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C: Repetitive rating, pulse width limited by junction temperature $T_{\text{J(MAX)}}=175^\circ\text{C}$.

D. The R_{JJA} is the sum of the thermal impedance from junction to case R_{JJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{\text{J(MAX)}}=175^\circ\text{C}$.

G. The maximum current rating is limited by bond-wires.

H. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

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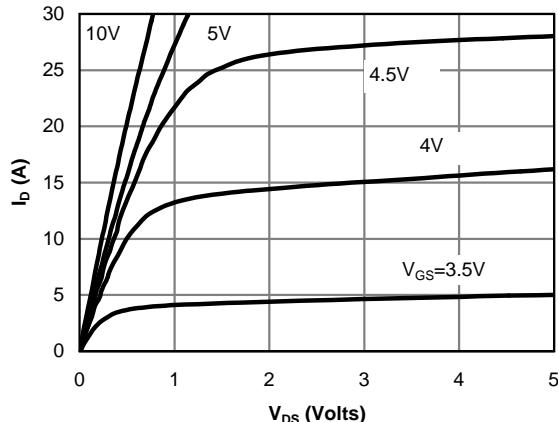
N-Channel MOSFET TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics

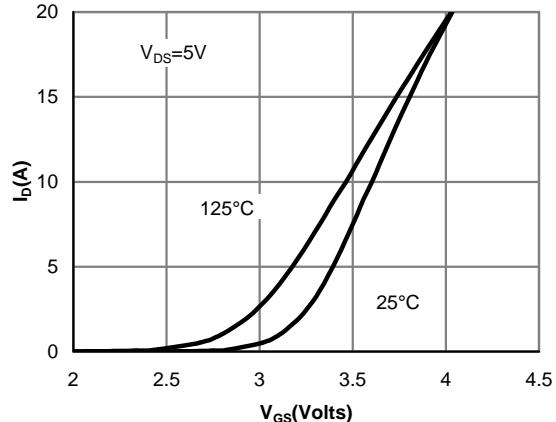


Figure 2: Transfer Characteristics

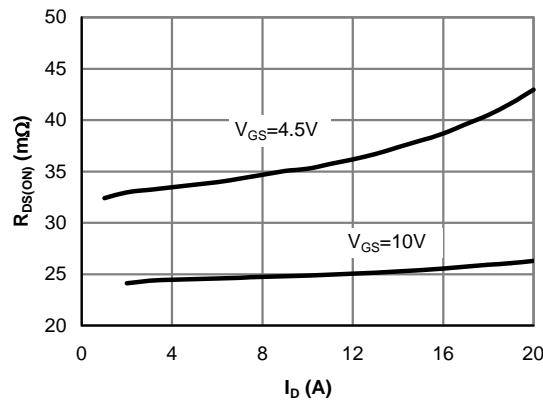


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

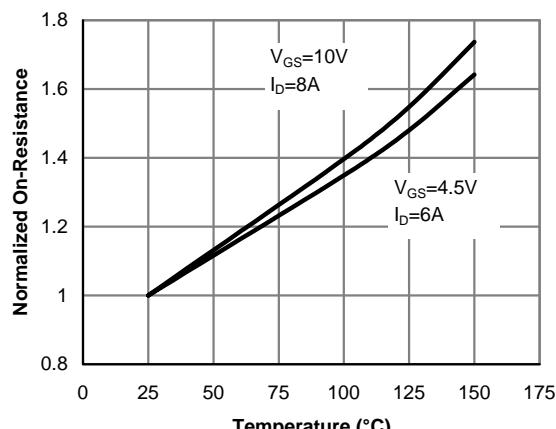


Figure 4: On-Resistance vs. Junction Temperature

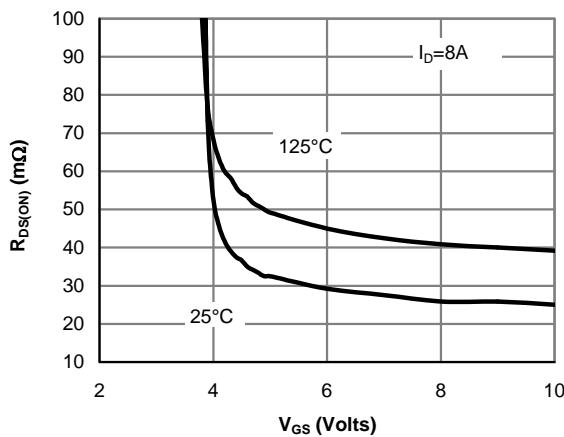


Figure 5: On-Resistance vs. Gate-Source Voltage

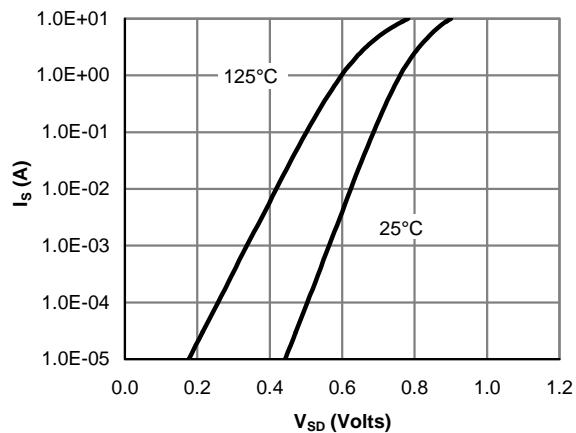


Figure 6: Body-Diode Characteristics

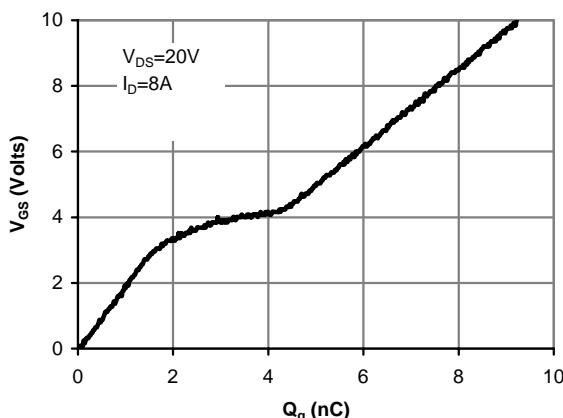
N-Channel MOSFET TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

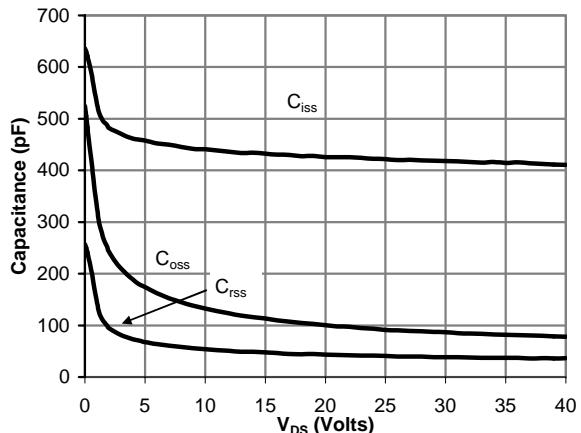


Figure 8: Capacitance Characteristics

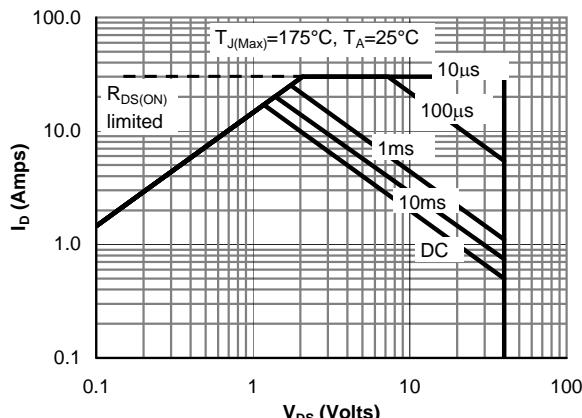


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

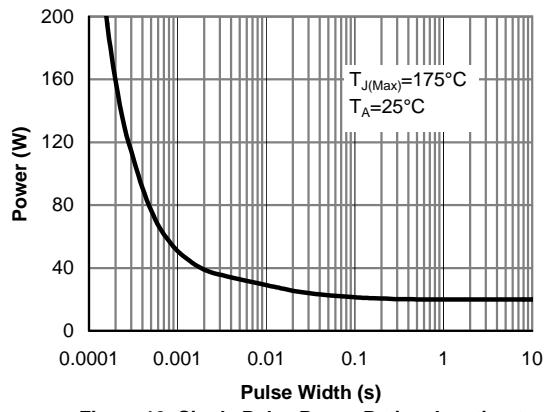


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

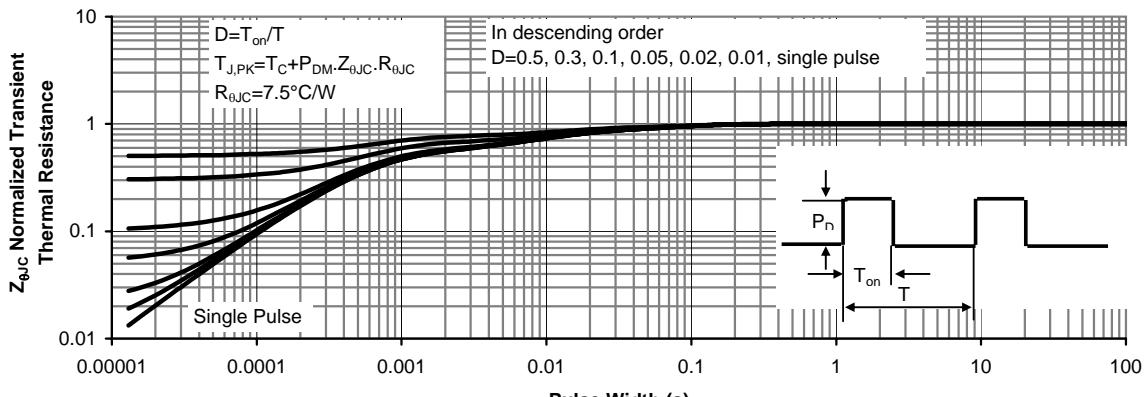


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

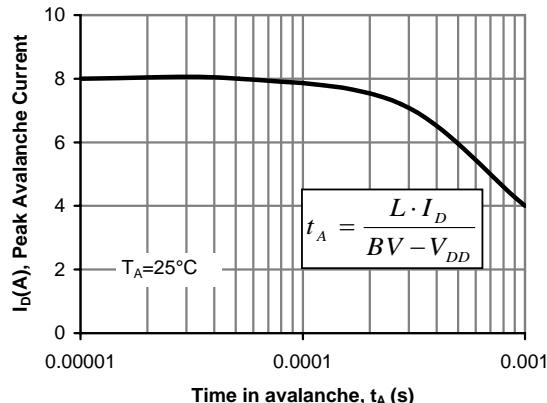
N-Channel MOSFET TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 12: Single Pulse Avalanche capability

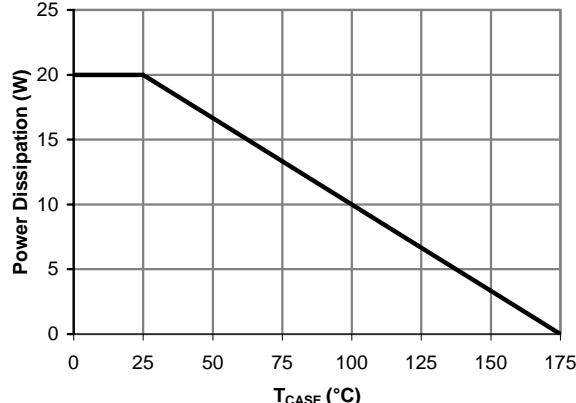


Figure 13: Power De-rating (Note B)

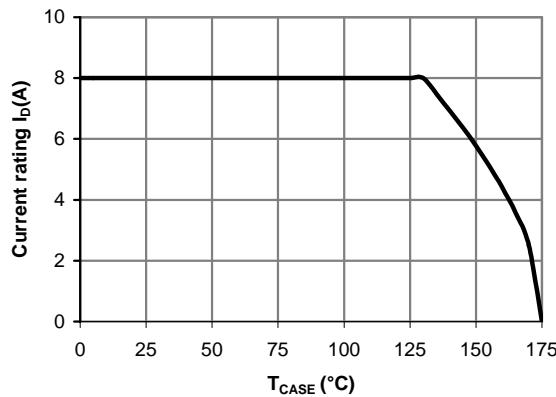


Figure 14: Current De-rating (Note B)

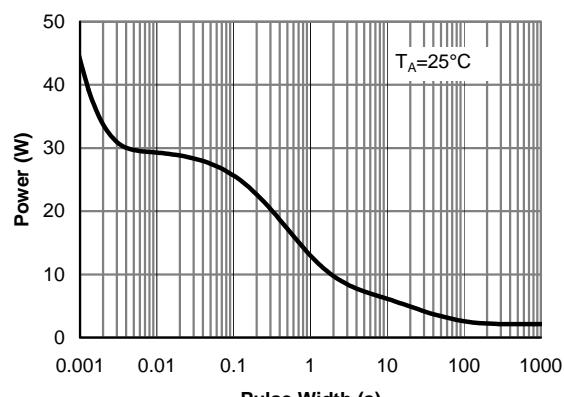


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

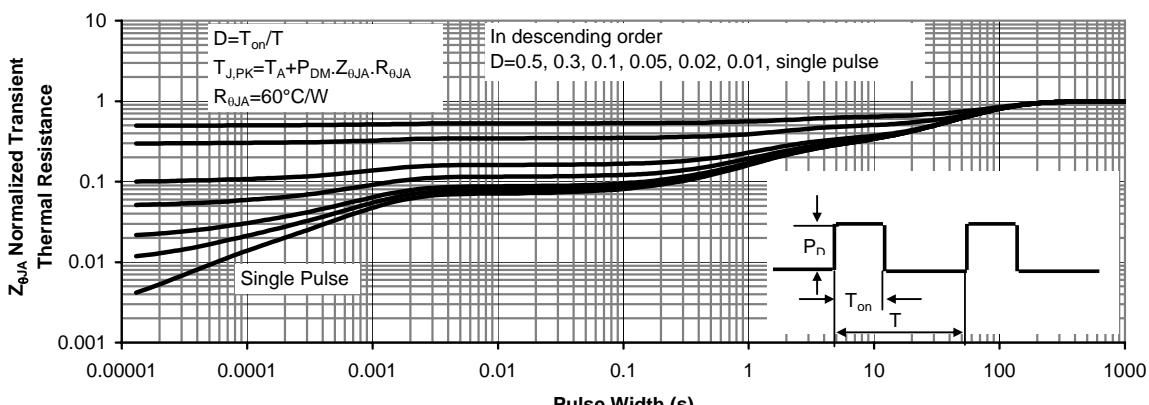


Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

P-Channel MOSFET Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-40			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-32\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			±100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1	-1.8	-3	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-10\text{V}, V_{DS}=-5\text{V}$	-30			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-8\text{A}$ $T_J=125^\circ\text{C}$		41 62	50	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-4\text{A}$			57 70	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-8\text{A}$		16		S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.75	-1	V
I_s	Maximum Body-Diode Continuous Current				-8	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-20\text{V}, f=1\text{MHz}$		657		pF
C_{oss}	Output Capacitance			143		pF
C_{rss}	Reverse Transfer Capacitance			63		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		6.5		Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge (10V)	$V_{GS}=-10\text{V}, V_{DS}=-20\text{V}, I_D=-8\text{A}$		14.1		nC
$Q_g(4.5\text{V})$	Total Gate Charge (4.5V)			7		nC
Q_{gs}	Gate Source Charge			2.2		nC
Q_{gd}	Gate Drain Charge			4.1		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=-10\text{V}, V_{DS}=-20\text{V}, R_L=2.5\Omega, R_{\text{GEN}}=3\Omega$		8		ns
t_r	Turn-On Rise Time			12.2		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			24		ns
t_f	Turn-Off Fall Time			12.5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-8\text{A}, dI/dt=100\text{A}/\mu\text{s}$		23.2		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-8\text{A}, dI/dt=100\text{A}/\mu\text{s}$		18.2		nC

A: The value of R_{qJA} is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation PDSM is based on R_{qJA} and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design, and the maximum temperature of 175°C may be used if the PCB allows it.

B. The power dissipation PD is based on $T_J(\text{MAX})=175^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C: Repetitive rating, pulse width limited by junction temperature $T_J(\text{MAX})=175^\circ\text{C}$.

D. The R_{qJA} is the sum of the thermal impedance from junction to case R_{qJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 ms pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_J(\text{MAX})=175^\circ\text{C}$.

G. The maximum current rating is limited by bond-wires.

H. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

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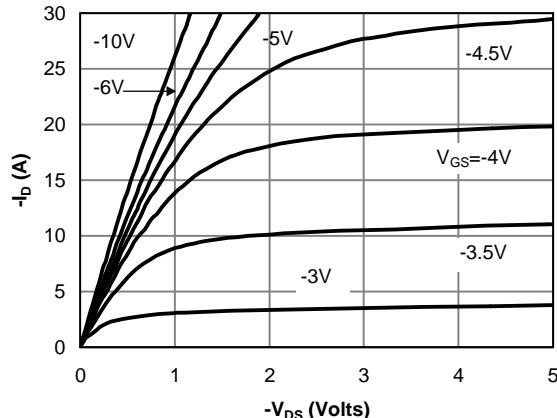
P-Channel MOSFET Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)


Fig 1: On-Region Characteristics

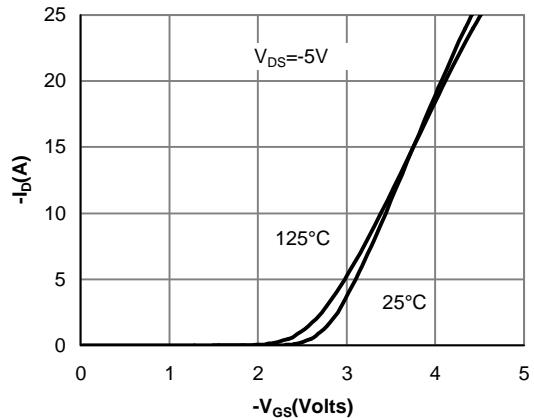


Figure 2: Transfer Characteristics

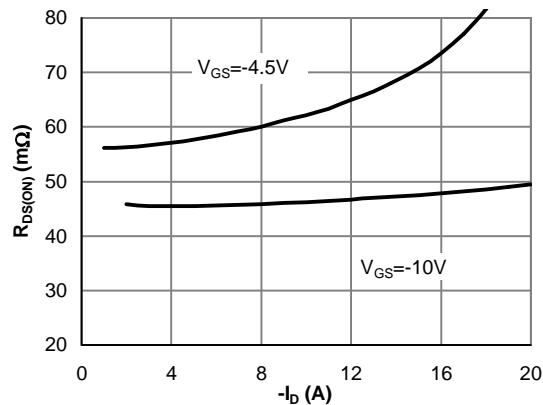


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

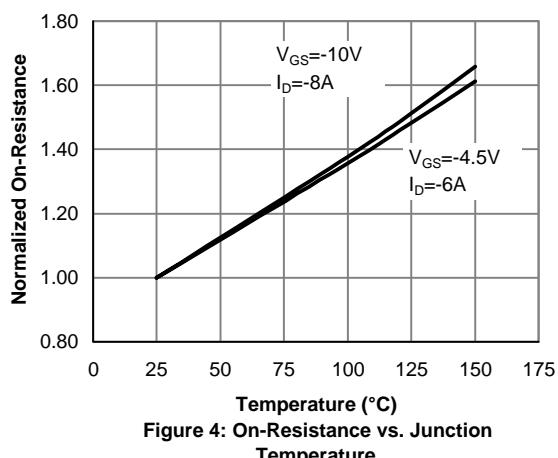


Figure 4: On-Resistance vs. Junction Temperature

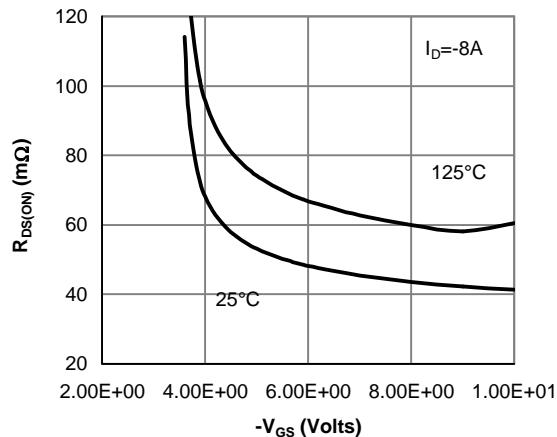


Figure 5: On-Resistance vs. Gate-Source Voltage

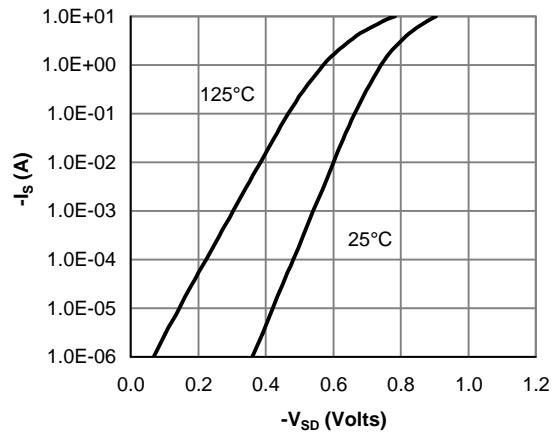
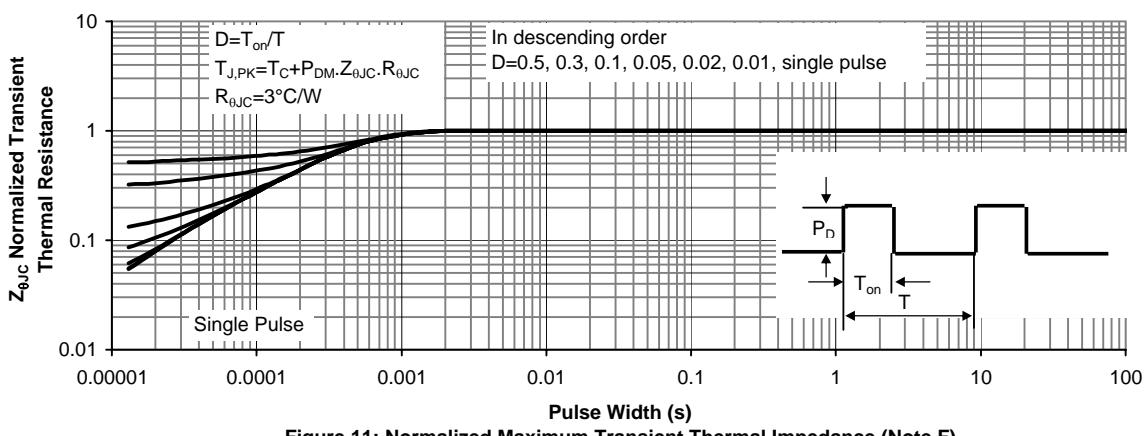
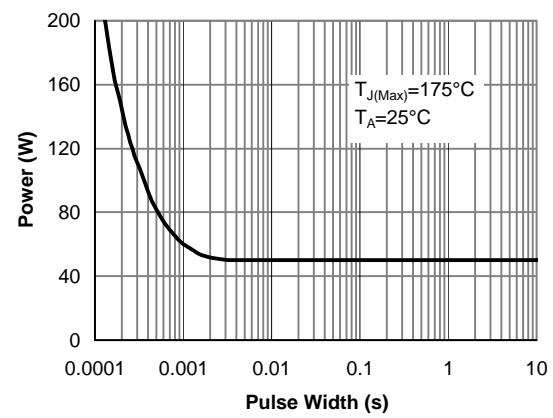
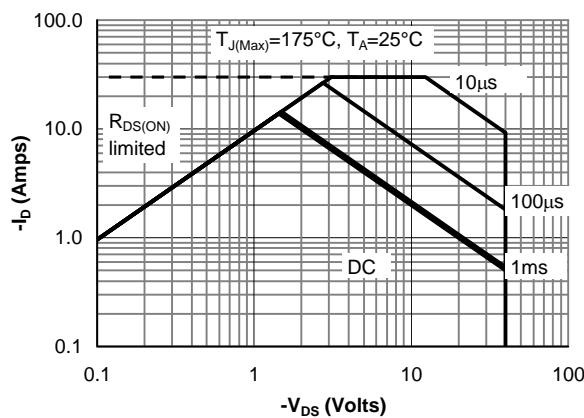
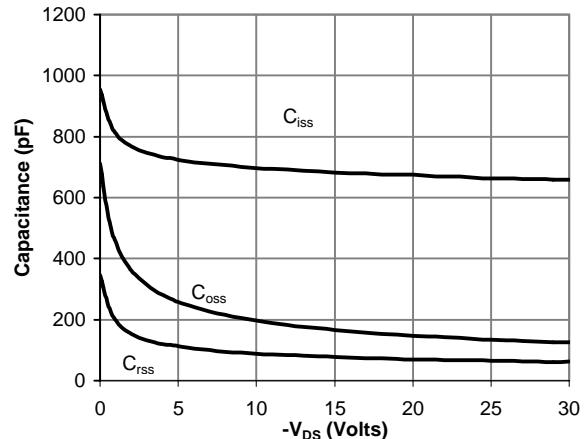
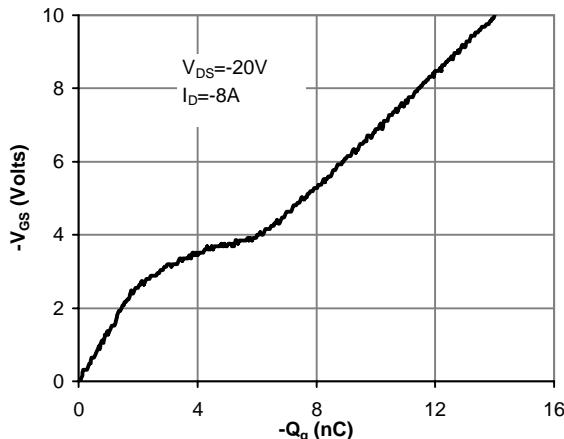


Figure 6: Body-Diode Characteristics

P-Channel MOSFET Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

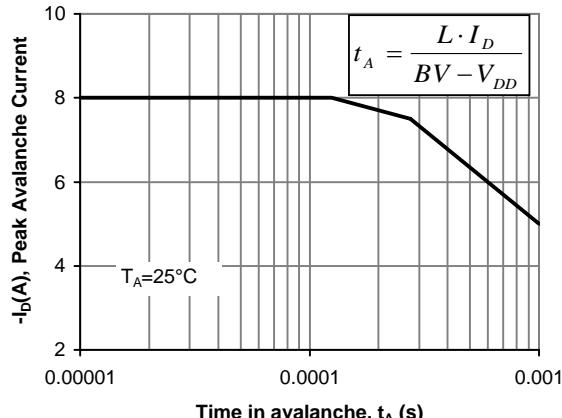
P-Channel MOSFET Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Figure 12: Single Pulse Avalanche capability

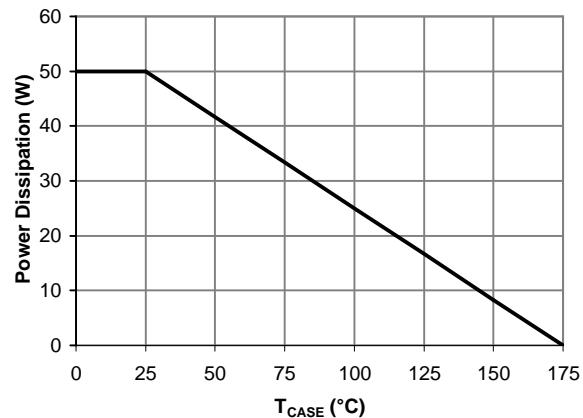


Figure 13: Power De-rating (Note B)

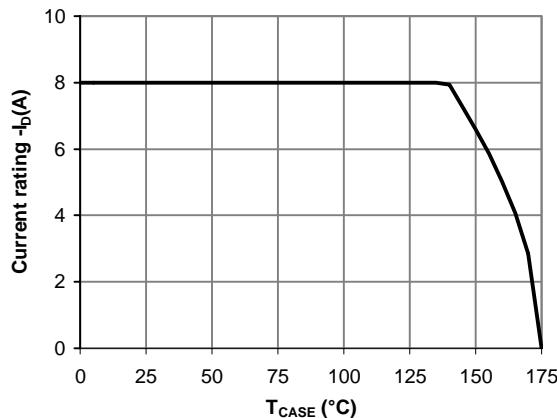


Figure 14: Current De-rating (Note B)

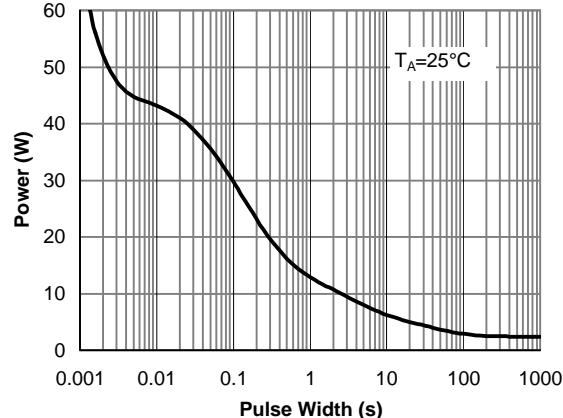


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

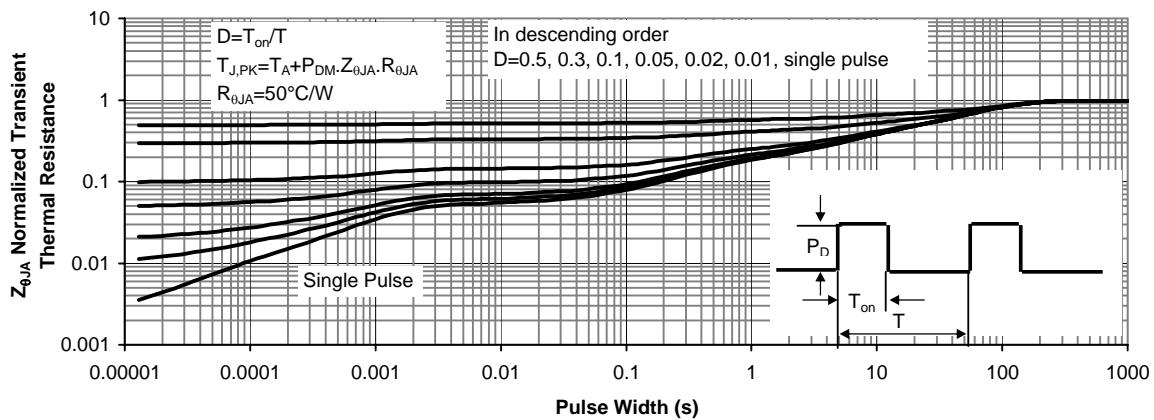


Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)